

# IRFP250B

## 200V N-Channel MOSFET

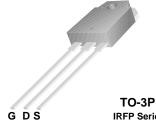
#### **General Description**

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar, DMOS technology.

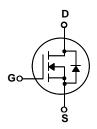
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters, switch mode power supplies, DC-AC converters for uninterrupted power supply and motor control.

#### **Features**

- 32A, 200V,  $R_{DS(on)}$  = 0.085 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 95 nC)
- Low Crss (typical 75 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability



**IRFP Series** 



# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		IRFP250B	Units
V <sub>DSS</sub>	Drain-Source Voltage		200	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25	°C)	32	А
	- Continuous (T <sub>C</sub> = 10	0°C)	20.3	А
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	128	А
V <sub>GSS</sub>	Gate-Source Voltage		± 30	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	600	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	32	А
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	20.4	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	5.5	V/ns
$P_{D}$	Power Dissipation (T <sub>C</sub> = 25°C) - Derate above 25°C		204	W
			1.63	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		0.61	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.24		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		40	°C/W

Symbol	Parameter	Test Conditions	S	Min	Тур	Max	Units
Off Cha	racteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		200			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced	I <sub>D</sub> = 250 μA, Referenced to 25°C		0.2		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 200 V, V <sub>GS</sub> = 0 V				10	μΑ
		V <sub>DS</sub> = 160 V, T <sub>C</sub> = 125°C	)			100	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$				100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30 V, V <sub>DS</sub> = 0 V		1		-100	nA
On Cha	racteristics						
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$		2.0		4.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 16 A			0.071	0.085	Ω
9FS	Forward Transconductance	V <sub>DS</sub> = 40 V, I <sub>D</sub> = 16 A	(Note 4)		27		S
C <sub>iss</sub>	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz			2600 330	3400 430	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance				75	100	pF
Switchi	ng Characteristics						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 100 V, I <sub>D</sub> = 32 A,			30	70	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$			240	490	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	1.6 2022			295	600	ns
t <sub>f</sub>	Turn-Off Fall Time		(Note 4, 5)		195	400	ns
Qg	Total Gate Charge	$V_{DS} = 160 \text{ V}, I_{D} = 32 \text{ A},$			95	123	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10 V			13		nC
$Q_{gd}$	Gate-Drain Charge	(Note 4, 5)		1	43		nC
Drain-S	Source Diode Characteristics ar	nd Maximum Rating	s				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current			-		32	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	Forward Current		-		128	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 32 A		1		1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V}, I_{S} = 32 \text{ A},$		-	220		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)			1.89		μC

- Notes: 
  1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 0.88mH,  $I_{AS} = 32A$ ,  $V_{DD} = 50V$ ,  $R_G = 25~\Omega$ , Starting  $T_J = 25^{\circ}C$  3.  $I_{SD} = 32A$ , di/dt  $\leq 300A/\mu$ s,  $V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^{\circ}C$  4. Pulse Test : Pulse width  $\leq 300\mu$ s, Duty cycle  $\leq 2\%$  5. Essentially independent of operating temperature

# **Typical Characteristics**

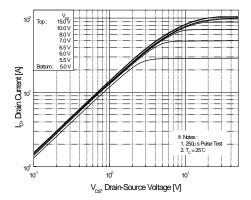


Figure 1. On-Region Characteristics

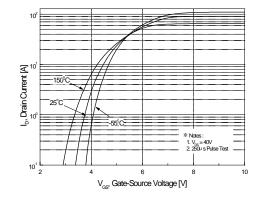


Figure 2. Transfer Characteristics

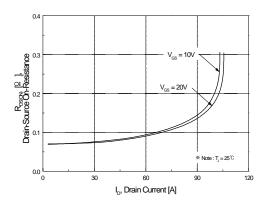


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

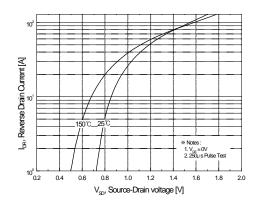


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

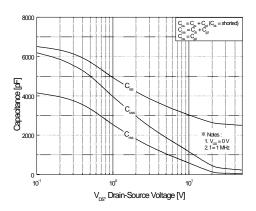


Figure 5. Capacitance Characteristics

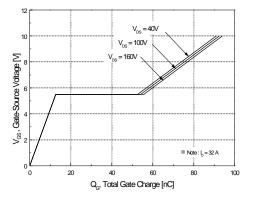


Figure 6. Gate Charge Characteristics

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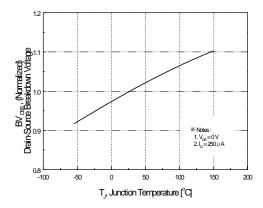
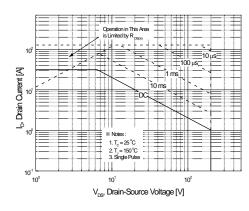


Figure 7. Breakdown Voltage Variation vs Temperature

Figure 8. On-Resistance Variation vs Temperature



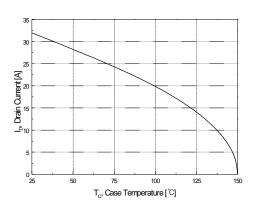


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

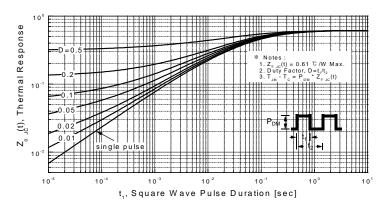
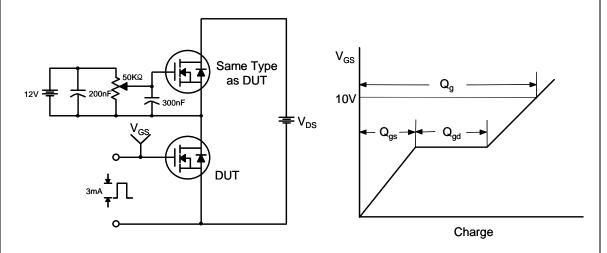
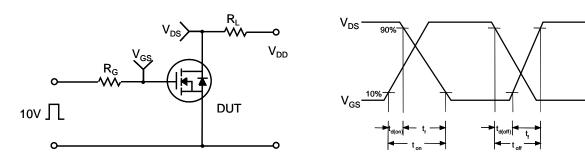


Figure 11. Transient Thermal Response Curve

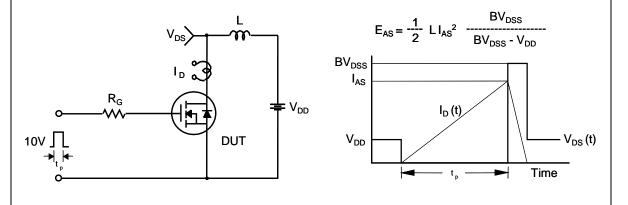
# **Gate Charge Test Circuit & Waveform**



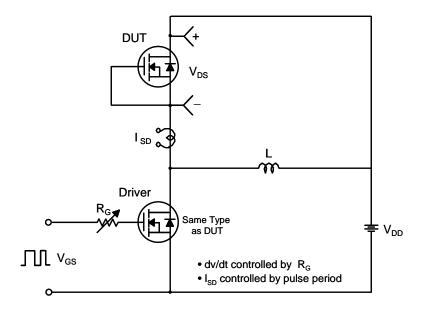
## **Resistive Switching Test Circuit & Waveforms**



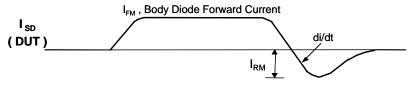
# **Unclamped Inductive Switching Test Circuit & Waveforms**



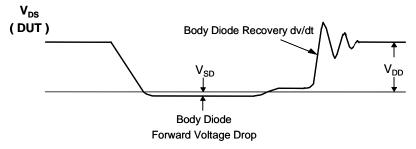
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

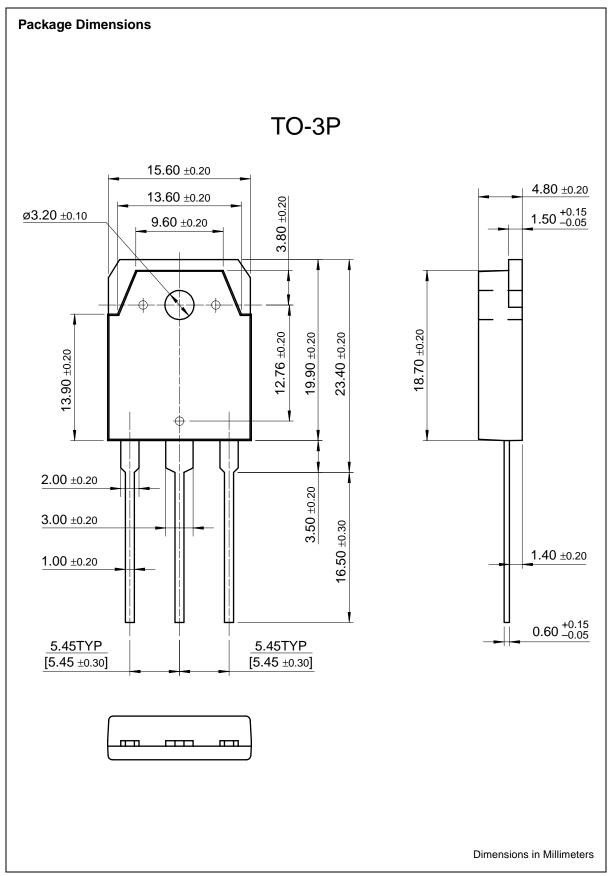






Body Diode Reverse Current





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